



## China Compound Semiconductor Materials Standards TC Meeting Agenda

China Spring Standards Meeting  
Wednesday, April 27<sup>th</sup>, 2022, 9:30-16:40

Virtual Meeting

<b>Time</b>	<b>Topic</b>	<b>Presenter</b>
9:00	<b>Registration</b>	
9:30	<b>Welcome / Call to Order</b> <ul style="list-style-type: none"> <li>Opening Remark</li> <li>Introductions</li> <li>Meeting Reminders</li> <li>Agenda Review</li> </ul>	Co-chair All SEMI Staff Co-chair
9:55	<b>Review and Approval of Previous Meeting Minutes</b>	SEMI Staff
10:00	<b>SEMI Staff Report</b>	SEMI Staff
10:05	<b>Liaison Reports</b> <ul style="list-style-type: none"> <li>North America CSM Committee</li> <li>Europe CSM Committee</li> <li>Japan CSM Committee</li> </ul>	SEMI Staff SEMI Staff SEMI Staff
10:20	<b>TF Reports</b> <ul style="list-style-type: none"> <li>SiC Epitaxial Wafer Task Force</li> <li>Silicon Carbide Substrate Task Force</li> </ul>	Gan FENG – Epiworld Min LU – MigeLab
10:40	<b>New TFOF Application</b> <ul style="list-style-type: none"> <li>TFOF Application &amp; Discussion</li> </ul>	Neng ZHANG – Sinopatt
11:30	<b>SEMI China TC Published Standards in 2022 Announcement</b> <ul style="list-style-type: none"> <li>SEMI HB4-0122, Revision to SEMI HB4-0913 (Reapproved 0419), Specification of Communication Interfaces for High Brightness LED Manufacturing Equipment (HB-LED ECI)</li> </ul>	
11:35	<b>Lunch</b>	
13:00	<b>Ballots Cycle 1-2022 Review</b> <ul style="list-style-type: none"> <li>Doc.6371C, Test Method for Determining Geometrical Parameters of Patterns on Patterned Sapphire Substrate</li> <li>Doc. 6693, New Standard:Specification for 4H-SiC Homoepitaxial Wafer</li> <li>Doc. 6767, Test Method for Flatness of Silicon Carbide Wafers by Optical Interference</li> <li>Doc. 6768, Test Method for Micropipe Density of Silicon Carbide Wafer by Laser Reflection</li> <li>Doc. 6769, Test Method for Residual Stress of Silicon Carbide Wafers by Photoelastic</li> </ul>	Jianzhe LIU – BST Gan FENG – Epiworld Min LU – MigeLab Min LU – MigeLab Min LU – MigeLab
16:30	<b>New Action Items &amp; Update</b>	SEMI Staff
16:35	<b>Next Meeting Date &amp; Locale</b> <ul style="list-style-type: none"> <li>Next Meeting Time of the China Compound Semiconductor Materials Standards Committee</li> </ul>	
16:40	<b>Adjournment</b>	